

FORM PTO 1449 (modified)			ATTY DOCKET NO. 03500.015727.		APPLICATION NO. 09/941,780	
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPLICANT Takeo Tsukamoto			
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			FILING DATE August 30, 2001		GROUP 2821 2828	
Date Submitted to PTO: [DATE]			U.S. PATENT DOCUMENTS			
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
W	6,472,814 B1	10/02	Yamanobe et al.	313	495	11/13/98
↑	5,847,495	12/98	Yamanobe et al.	313	310	
	5,066,883	11/91	Yoshioka et al.	313	309	
	6,455,021 B1	09/02	Saito	423	447.3	07/20/99
	6,471,936 B1	10/02	Chen et al.	423	658.2	03/02/00
	6,283,812 B1	09/01	Jin et al.	445	24	01/25/99
	4,816,289	03/89	Komatsu et al.	423	447.3	
	5,443,859	08/95	Nagata	427	122	
	5,618,875	04/97	Baker et al.	524	495	
	5,690,997	11/97	Grow	427	249	
	6,129,602	10/00	Yamanobe	445	24	
	6,228,904 B1	05/01	Yadav et al.	523	210	
	6,333,016 B1	12/01	Resasco et al.	423	447.3	9/3/99
	6,413,487 B1	07/02	Resasco et al.	423	447.3	6/2/00
	6,445,006 B1	09/02	Brandes et al.	257	76	7/27/99
	5,981,305	11/99	Hattori	438	20	
	6,290,564 B1	9/01	Talin et al.	445	50	9/30/99
	5,458,784	10/95	Baker et al.	210	674	5/3/00
↓	6,331,690 B1	12/01	Yudasaka et al.	219	121.6	
W	5,965,267	10/99	Nolan et al.	428	408	
EXAMINER David W			DATE CONSIDERED 11/4/04			

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U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
D	6,390,612 B1	05/02	Kotaki et al.	347	85	
↑	5,872,541	02/99	Yoshioka et al.	345	74	
↑	5,543,684	08/96	Kumar et al.	313	495	
↑	5,551,903	9/96	Kumar et al.	445	24	
↑	4,900,483	2/90	Witzke et al.	264	29.2	
↑	5,500,200	3/96	Mandeville et al.	423	447.3	
↑	5,726,524	3/98	Debe	313	309	
↑	2002/0009637 A1	1/24/02	Murakami et al	429	213	2/5/01
↑	2002/0047562 A1	04/25/02	Kitamura et al.	315	169.3	05/29/01
↑	5,770,918	6/98	Kawate et al.	313	495	
↑	5,185,554	2/93	Nomura et al.	313	495	
✓	2002/0146958 A1	10/02	Ono et al.	445	24	
D	2003/0048056 A1	3/03	Kitamura et al.	313	311	

EXAMINER <b>David Jn</b>	DATE CONSIDERED <b>11/4/04</b>
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				GROUP <b>-2821 2828</b>	

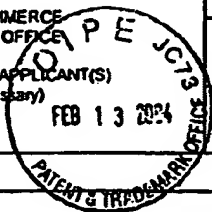
FOREIGN PATENT DOCUMENTS						
NO.	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
2	11-194134	07/99	Japan	G01N	37/00	Abst., European Equivalent 0 913 508 A3
1	11-139815	05/99	Japan	G01B	31/02	Abst.
	0 535 953 B1	01/96	EPO	H01J	1/30	English
	1 122 344 A2	08/01	EPO	D01F	9/127	English
	0 758 028 B1	09/11/02	EPO	D01F	9/127	English
	11-232997	08/27/99	Japan	H01J	1/30	European Counterpart 0 936 650
	1 022 763 A1	7/00	EPO	H01J	9/02	English
	2000-223005	8/00	Japan	H01J	1/304	Abst. & Counterpart U.S. Patent 6,283,812
	0 836 217 A1	04/98	EPO	H01J	29/94	English
	WO 99/58748	11/99	PCT	D01F	9/127	English
	CN 1181607A	5/98	China			English Counterparts 0 836 217 & 09/58748
	1 102 299 A1	5/01	EPO	H01J	1/30	English
	0 913 508 A3	5/99	EPO	D01F	9/127	English
	1 096 533 A1	5/01	EPO	H01J	9/02	English
	WO 01/26130	4/01	PCT	H01J	9/02	English
✓	GB 2 308 495 A	6/97	UK	H01J	1/20	English
2	1 120 877 A1	8/01	EPO	H02G	5/06	English

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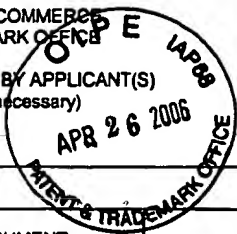
FOREIGN PATENT DOCUMENTS						
U	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	1-309242	12/89	Japan	H01J	37/06	Abst.
	11-162334	6/99	JAPAN	H01J	9/02	Abst.
	2000-57934	2/00	JAPAN	H01J	1/304	Abst.
	2000-86216	3/00	JAPAN	C01B	31/02	Abst.
	2000-90809	3/00	JAPAN	H01J	1/304	Abst.
	2001-288625 A	10/01	Japan	D01F	9/127	Abst., Counterpart U.S. Patent 2002/00809837 & EP 1 122 344
	0 433 507 A1	6/91	EPO	D01F	9/127	English
	03-260119	11/91	Japan	D01F	9/127	Abst. & Counterpart U.S. Patent 4,900,483
	2001-52598	2/01	Japan	H01J	1/316	Abst.
	2000-95509	4/00	Japan	C01B	31/02	Abst.
	0 451 208 B1	3/00	EPO	D01F	9/12	English
	2000-208028	7/00	Japan	H01J	1/304	Abst.
	0 936 650 A1	8/01	EPO	H01J	3/02	English
	08-298068	11/96	Japan	H01J	1/30	Abst.
2	2001-162600	6/19/01	Japan	B82B	1/00	Abst.

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OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)			
<i>R</i>		W. Zhu Et Al., <i>Electron Field Emission From Nanostructured Diamond and Carbon Nanotubes</i> , Solid State Electronics, Vol. 45, 2001, pp. 921-928	
↑		J.M. Bonard Et Al., <i>Field Emission From Carbon Nanotubes: The First Five Years</i> , Solid State Electronics, Vol. 45, 2001, pp. 893-914	
↑		A.M. Rao et al., "In Situ-grown Carbon Nanotube Array of with Excellent Field Emission Characteristics," Applied Physics Letter, Vol. 76, No. 25, pp. 3813-3815 (2000).	
↑		Cheol Jin Lee et al., "Carbon Nanofibers Grown on Sodalime Glass at 500 °C Using Thermal Chemical Vapor Deposition," Chemical Physics Letters 340, pp. 413-418 (2001).	
↓		Sashiro Uemura et al., "Carbon Nanotube FED with Graphite-Nano-Fiber Emitters," ISSN 1083-1312, pp. 398-401, 2000.	
<i>R</i>		Q. H. Wang et al., "A Nanotube-Based Field-Emission Flat Panel Display," Applied Physics Letters, Vol. 72, No. 22, June 1998, pp. 2912-2913	
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<i>David ✓</i>		<i>11/4/04</i>	

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U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
d		2003/0048057 A1	3/13/03	Oyama et al.	313	311	—	
d		2002/0031972 A1	3/14/02	Kitamura et al.	445	3	—	
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	
d	JP	2000-207983	07/28/00	Japan	—	—	Abstract	
d	JP	2002-500415	01/08/02	Japan	—	—	No	
d	WO	01/93292 A1	12/6/01	PCT	—	—	English	
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d		Xucun Ma et al., Polymerized carbon nanobells and their field-emission properties, Applied Physics Letters, 15 Nov. 1999, Vol. 75, No. 20, pp. 3105-3107.						
EXAMINER		David VW			DATE CONSIDERED			7/10/06

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D	6,624,589 B2	09/23/03	Kitamura et al.	315	169.3	
↑	6,628,053 B1	09/30/03	Den et al.	313	310	
	6,626,719 B2	09/30/03	Ono et al.	445	24	
	2002/0060516 A1	05/23/02	Kawate et al.	313	495	
	2002/0057045 A1	05/16/02	Tsukamoto	313	309	
	2002/0047513 A1	04/25/02	Nomura	313	495	
	2003/0006684 A1	01/09/03	Kawate et al.	313	311	
↓	2003/0048055 A1	03/13/03	Ishikura et al.	313	311	
D	2003/0057860 A1	03/27/03	Tsukamoto	315	169.3	
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